U.S.	PATENT	DOCUMENTS
		NAME

*EXAMINER			3.5. PATEINT DOCUMENTO			FILING DATE
INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS		IF APPROPRIATE
AN	2004/0263185	12/2004	Cho et al.	324	636	
1	2004/0114913	06/2004	Kume	386	125	
	2003/0053400	03/2003	Cho et al.	369	126	
	2004/0027935	02/2004	Cho et al.	369	126	
	2003/0021213	01/2003	Hagiwara, Yoshiaki	369	101	·
	4,320,491	03/1982	Rustman, James C.	369	126	
	5,418,029	05/1995	Yamamoto et al.	428	64.2	
	5,481,527	01/1996	Kasanuki et al.	369	126	
	5,646,932	07/1997	Kuribayashi et al.	369	126	
	5,751,685	05/1998	Yi, You-Wen	369	126	
	5,914,920	06/1999	Yokogawa	369	275.3	
	5,946,284	08/1999	Chung et al.	369	126	
	6,477,132	11/2002	Azuma et al.	369	. 126	
	6,510,130	01/2003	Hayashi et al.	369	275.3	
	6,515,957	02/2003	Newns et al.	369	126	
	6,653,630	11/2003	Rosenman et al.	250	306	
	6,762,402	07/2004	Choi et al.	250	234	
	6,841,220	01/2005	Onoe et al.	428	66.7	
	6,912,193	06/2005	Cho et al.	369	126	
	6,965,545	11/2005	Hino et al.	369	13.54	
***	7,065,033	06/2006	Onoe et al.	369	126	L
AN	7,149,180	12/2006	Onoe et al.	369	276	

•		FOREIGN	PATENT DOCUMENTS				
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSL YES	ATION NO
AN	2003085969	03/2003	JР			ABSTRACT	
AN	08-075806	03/1996	JP			ABSTRACT	
AN .	10-334525	12/1998	JP			ABSTRACT	
AN	56-107338	08/1981	JР		1	ABSTRACT	

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

62th Japan Society of Applied Physics Lecture Meeting (2001.9 Aichi Institute of Technology) 12p-ZR-2.

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10/657,715

CHO et al. FILING DATE

TC/A.U.

September 9, 2003

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			U.S. PATENT	DOCUMENTS						
XAMINER INITIAL	DOCUMENT NUMBER	DATE		NAME	CLA	ASS	SUBC	LASS	FILING IF APPRO	DATE OPRIA
AN	5,488,602	01/1996	,	Yamano et al.	30	59		26		
5,808,977		09/1998	K	oyanagi et al.	36	59	12	27		
		03/2001	F	urukawa et al.	5.5	56	45	50		
	2005/0122886	06/2005	Т	akahashi et al.	30	59	12	26		
	2005/0099895	05/2005		Maeda et al.	36	59	13.	01		
	2005/0098532	05/2005		Onoe et al.	2	16	2	2		
	20050047288	03/2005		Maeda et al.	30	59	53.	25		
	2004/0252621	12/2004		Cho et al.	36	59	12	26		
	2004/0105380	06/2004		Cho et al.	36	59	12	26		
	2004/0105373	06/2004		Maeda et al.	30	59	10)1		
	2004/0090903	05/2004		Cho et al.	30	59	12	26		
	20040042351	03/2004		Onoe et al.	30	59	13.	.01		
, ,	20020131669	09/2002		Onoe et al.	- 38	35	1	4		
	20020118906	08/2002		Onoe	38	35	1	4		
AN	20020105249	08/2002		Yoshida et al.	3	10	31	11		
1										
		FOR	REIGN PATEN	T DOCUMENTS						
									TRANSI	LATIC
	DOCUMENT	DATE		COUNTRY	CLA	ASS	SUBC	LASS	YES	N
AN	57-200956	12/1982	· · · · · · · · · · · · · · · · · · ·	JP					ABSTRACT	
AN	1 484 256	09/1977		GB						
AW	1 404 230	09/19//					┝┈╜	<u> </u>		
			·							_
							 -			
		L1					<u> </u>		<u> </u>	
				or, Title, Date, Perti					 	
AN	Kazuta et al, "Determin				sing scanni	ng n	onlinea	ır diele	ectric	
AIN	microscopy", Journal of	European Co	eramic Society 2	1 (2001) 1581-1584.						
AN	The Institution of Electr	ical Engineer	rs, Stevenage, G	B; 1 June 2002; Hirana	iga et al, "N	lano-	Sized i	nverte	d domain	ໄ ໄດລລ
AN	formation in stoichiome	tric Li IaO/si	ub3/single crysta	l using Scanning Nonl	inear Diele	curic	VIICIOS	copy	, APUUZZ	2922
2.37	Cho et al, "Scanning no	nlinear dielec	tric microscopy	with nanometer resolu	tion", Jourt	nai oi	Europ	ean C	eramic S	ociei
AN	21 (2001) 2131-2134.	 		1: 1	· · · · · · · · · · · · · · · · · · ·	<u> </u>	har 20	2001	IEE NA	NO
AN		Cho et al., "Nano domain engineering using scanning nonlinear dielectric microscopy, October 29, 2001, IEE-NANO								
	2001, pages 352-357.					-				
					,		 -			
	/*	LI NEYZA	DT/			02/	15/2	007		
xaminer) / A	TT METTW	N.T./	Date Considered	1	/	/-			

Examiner: Initial it reference considered, whether or not citation is in conformance with MPEP 609; Oraw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

Date Considered

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